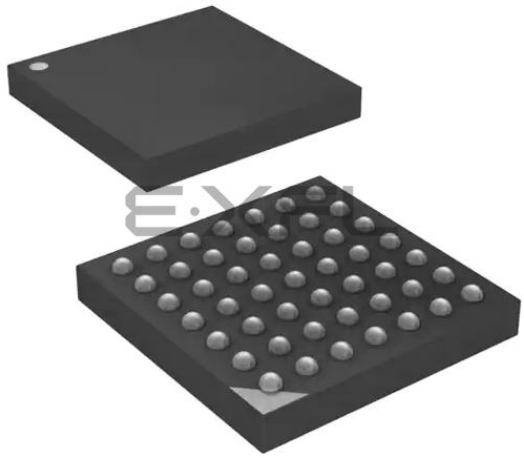

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	34
Program Memory Size	16KB (8K x 16)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 12x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	0°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	49-VFBGA
Supplier Device Package	49-VFBGA (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega16a4u-cn

17. TC2 - Timer/Counter Type 2

17.1 Features

- Six eight-bit timer/counters
  - Three Low-byte timer/counter
  - Three High-byte timer/counter
- Up to eight compare channels in each Timer/Counter 2
  - Four compare channels for the low-byte timer/counter
  - Four compare channels for the high-byte timer/counter
- Waveform generation
  - Single slope pulse width modulation
- Timer underflow interrupts/events
- One compare match interrupt/event per compare channel for the low-byte timer/counter
- Can be used with the event system for count control
- Can be used to trigger DMA transactions

17.2 Overview

There are four Timer/Counter 2. These are realized when a Timer/Counter 0 is set in split mode. It is then a system of two eight-bit timer/counters, each with four compare channels. This results in eight configurable pulse width modulation (PWM) channels with individually controlled duty cycles, and is intended for applications that require a high number of PWM channels.

The two eight-bit timer/counters in this system are referred to as the low-byte timer/counter and high-byte timer/counter, respectively. The difference between them is that only the low-byte timer/counter can be used to generate compare match interrupts, events and DMA triggers. The two eight-bit timer/counters have a shared clock source and separate period and compare settings. They can be clocked and timed from the peripheral clock, with optional prescaling, or from the event system. The counters are always counting down.

PORTC, and PORTD each has one Timer/Counter 2.

Notation of these are TCC2 (Time/Counter C2) and TCD2, respectively.

32.1.5 Communication functions

SCL	Serial Clock for TWI
SDA	Serial Data for TWI
SCLIN	Serial Clock In for TWI when external driver interface is enabled
SCLOUT	Serial Clock Out for TWI when external driver interface is enabled
SDAIN	Serial Data In for TWI when external driver interface is enabled
SDAOUT	Serial Data Out for TWI when external driver interface is enabled
XCKn	Transfer Clock for USART n
RXDn	Receiver Data for USART n
TXDn	Transmitter Data for USART n
SS	Slave Select for SPI
MOSI	Master Out Slave In for SPI
MISO	Master In Slave Out for SPI
SCK	Serial Clock for SPI
D-	Data- for USB
D+	Data+ for USB

32.1.6 Oscillators, Clock and Event

TOSCn	Timer Oscillator pin n
XTALn	Input/Output for Oscillator pin n
CLKOUT	Peripheral Clock Output
EVOUT	Event Channel Output
RTCOUT	RTC Clock Source Output

32.1.7 Debug/System functions

RESET	Reset pin
PDI_CLK	Program and Debug Interface Clock pin
PDI_DATA	Program and Debug Interface Data pin

Mnemonics	Operands	Description	Operation	Flags	#Clocks
CLZ		Clear Zero Flag	Z ← 0	Z	1
SEI		Global Interrupt Enable	I ← 1	I	1
CLI		Global Interrupt Disable	I ← 0	I	1
SES		Set Signed Test Flag	S ← 1	S	1
CLS		Clear Signed Test Flag	S ← 0	S	1
SEV		Set Two's Complement Overflow	V ← 1	V	1
CLV		Clear Two's Complement Overflow	V ← 0	V	1
SET		Set T in SREG	T ← 1	T	1
CLT		Clear T in SREG	T ← 0	T	1
SEH		Set Half Carry Flag in SREG	H ← 1	H	1
CLH		Clear Half Carry Flag in SREG	H ← 0	H	1
MCU control instructions					
BREAK		Break	(See specific descr. for BREAK)	None	1
NOP		No Operation		None	1
SLEEP		Sleep	(see specific descr. for Sleep)	None	1
WDR		Watchdog Reset	(see specific descr. for WDR)	None	1

Notes:
1. Cycle times for Data memory accesses assume internal memory accesses, and are not valid for accesses via the external RAM interface.
2. One extra cycle must be added when accessing Internal SRAM.

Table 36-69. Current consumption for modules and peripherals.

Symbol	Parameter	Condition [1]		Min.	Typ.	Max.	Units
I_{CC}	ULP oscillator				1.0		µA
	32.768kHz int. oscillator				29		µA
	2MHz int. oscillator				85		µA
		DFLL enabled with 32.768kHz int. osc. as reference			120		
	32MHz int. oscillator				300		µA
		DFLL enabled with 32.768kHz int. osc. as reference			465		
	PLL	20x multiplication factor, 32MHz int. osc. DIV4 as reference			320		µA
	Watchdog timer				1.0		µA
	BOD	Continuous mode			138		µA
		Sampled mode, includes ULP oscillator			1.0		
	Internal 1.0V reference				103		µA
	Temperature sensor				100		µA
	ADC	250ksps V_{REF} = Ext ref			3.0		mA
			CURRLIMIT = LOW		2.6		
			CURRLIMIT = MEDIUM		2.1		
			CURRLIMIT = HIGH		1.6		
	DAC	250ksps V_{REF} = Ext ref No load	Normal mode		1.9		mA
			Low power mode		1.1		
	AC	High speed mode			330		µA
		Low pPower mode			130		
	DMA	615KBps between I/O registers and SRAM			108		µA
	Timer/counter				16		µA
	USART	Rx and Tx enabled, 9600 BAUD			2.5		µA
	Flash memory and EEPROM programming				8.0		mA

Note: 1. All parameters measured as the difference in current consumption between module enabled and disabled. All data at V_{CC} = 3.0V, Clk_{SYS} = 1MHz external clock without prescaling, T = 25°C unless other conditions are given.

36.4.8 Analog Comparator Characteristics

Table 36-111. Analog Comparator characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{off}	Input offset voltage			<±10		mV
I_{lk}	Input leakage current			<1		nA
	Input voltage range		-0.1		AV_{CC}	V
	AC startup time			100		µs
V_{hys1}	Hysteresis, none			0		mV
V_{hys2}	Hysteresis, small	mode = High Speed (HS)		13		mV
		mode = Low Power (LP)		30		
V_{hys3}	Hysteresis, large	mode = HS		30		mV
		mode = LP		60		
t_{delay}	Propagation delay	V_{CC} = 3.0V, T= 85°C mode = HS		30	90	ns
		mode = HS		30		
		V_{CC} = 3.0V, T= 85°C mode = LP		130	500	
		mode = LP		130		
	64-level voltage scaler	Integral non-linearity (INL)		0.3	0.5	lsb

36.4.9 Bandgap and Internal 1.0V Reference Characteristics

Table 36-112. Bandgap and Internal 1.0V reference characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC or DAC	1 Clk_{PER} + 2.5µs			µs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T= 85°C, after calibration	0.99	1.0	1.01	V
	Variation over voltage and temperature	Relative to T= 85°C, V_{CC} = 3.0V		±1.5		%

36.4.10 Brownout Detection Characteristics

Table 36-113. Brownout detection characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{BOT}	BOD level 0 falling V_{CC}		1.50	1.62	1.72	V
	BOD level 1 falling V_{CC}			1.8		
	BOD level 2 falling V_{CC}			2.0		
	BOD level 3 falling V_{CC}			2.2		
	BOD level 4 falling V_{CC}			2.4		
	BOD level 5 falling V_{CC}			2.6		
	BOD level 6 falling V_{CC}			2.8		
	BOD level 7 falling V_{CC}			3.0		
t_{BOD}	Detection time	Continuous mode		0.4		µs
		Sampled mode		1000		
V_{HYST}	Hysteresis			1.2		%

36.4.11 External Reset Characteristics

Table 36-114. External reset characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{EXT}	Minimum reset pulse width		1000	95		ns
V_{RST}	Reset threshold voltage (V_{IH})	V_{CC} = 2.7 - 3.6V	0.60×V_{CC}			V
		V_{CC} = 1.6 - 2.7V	0.60×V_{CC}			
	Reset threshold voltage (V_{IL})	V_{CC} = 2.7 - 3.6V			0.50×V_{CC}	
		V_{CC} = 1.6 - 2.7V			0.40×V_{CC}	
R_{RST}	Reset pin Pull-up Resistor			25		kΩ

36.4.12 Power-on Reset Characteristics

Table 36-115. Power-on reset characteristics.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{POT-} (1)	POR threshold voltage falling V_{CC}	V_{CC} falls faster than 1V/ms	0.4	1.0		V
		V_{CC} falls at 1V/ms or slower	0.8	1.0		
V_{POT+}	POR threshold voltage rising V_{CC}			1.3	1.59	mV

Note: 1. V_{POT-} values are only valid when BOD is disabled. When BOD is enabled V_{POT-} = V_{POT+}.

Table 36-127. SPI timing characteristics and requirements.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{SCK}	SCK Period	Master		(See Table 21-4 in XMEGA AU Manual)		ns
t_{SCKW}	SCK high/low width	Master		0.5×SCK		
t_{SCKR}	SCK Rise time	Master		2.7		
t_{SCKF}	SCK Fall time	Master		2.7		
t_{MIS}	MISO setup to SCK	Master		10		
t_{MIH}	MISO hold after SCK	Master		10		
t_{MOS}	MOSI setup SCK	Master		0.5×SCK		
t_{MOH}	MOSI hold after SCK	Master		1		
t_{SSCK}	Slave SCK Period	Slave	4×t Clk_{PER}			
t_{SSCKW}	SCK high/low width	Slave	2×t Clk_{PER}			
t_{SSCKR}	SCK Rise time	Slave			1600	
t_{SSCKF}	SCK Fall time	Slave			1600	
t_{SIS}	MOSI setup to SCK	Slave	3			
t_{SIH}	MOSI hold after SCK	Slave	t Clk_{PER}			
t_{SSS}	$\overline{SS}$ setup to SCK	Slave	21			
t_{SSH}	$\overline{SS}$ hold after SCK	Slave	20			
t_{SOS}	MISO setup SCK	Slave		8		
t_{SOH}	MISO hold after SCK	Slave		13		
t_{SOSS}	MISO setup after $\overline{SS}$ low	Slave		11		
t_{SOSH}	MISO hold after $\overline{SS}$ high	Slave		8		

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq 100kHz$	0		3.45	µs
		$f_{SCL} > 100kHz$	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq 100kHz$	250			ns
		$f_{SCL} > 100kHz$	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq 100kHz$	4.0			µs
		$f_{SCL} > 100kHz$	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq 100kHz$	4.7			µs
		$f_{SCL} > 100kHz$	1.3			

Notes:
1. Required only for $f_{SCL} > 100kHz$.
2. C_b = Capacitance of one bus line in pF.
3. f_{PER} = Peripheral clock frequency.

37.1.1.3 Power-down mode supply current

Figure 37-15. Power-down mode supply current vs. temperature.
All functions disabled.

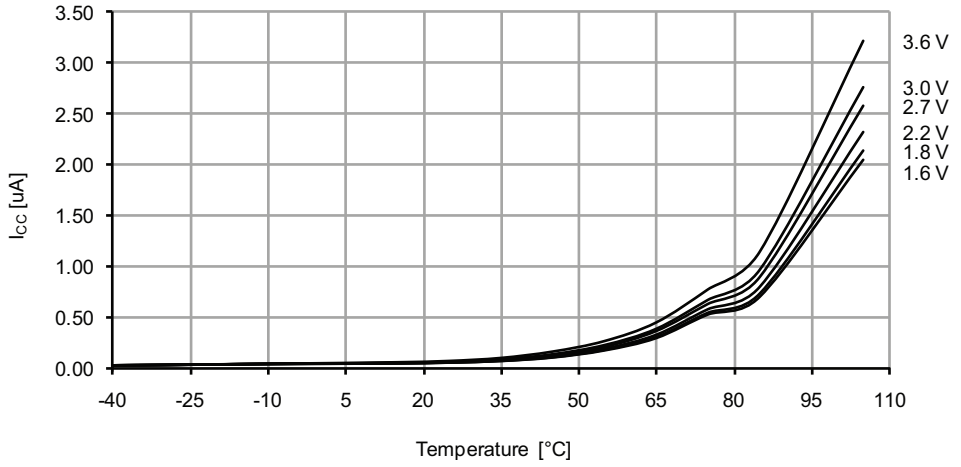


Figure 37-16. Power-down mode supply current vs. V_{CC}.
All functions disabled.

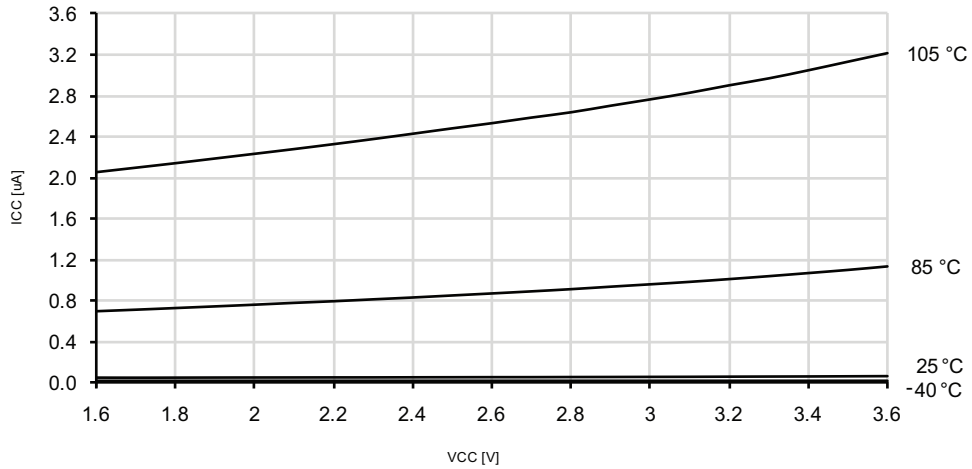


Figure 37-74. 2MHz internal oscillator frequency vs. temperature.

DFLL enabled, from the 32.768kHz internal oscillator .

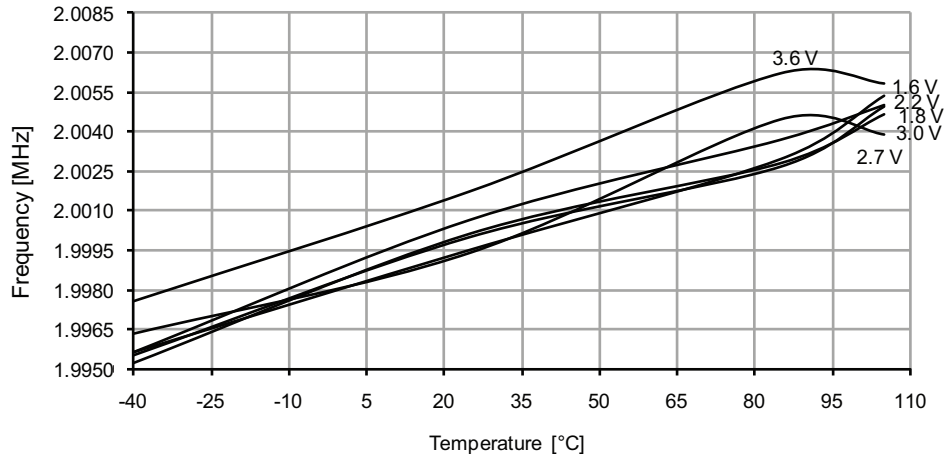
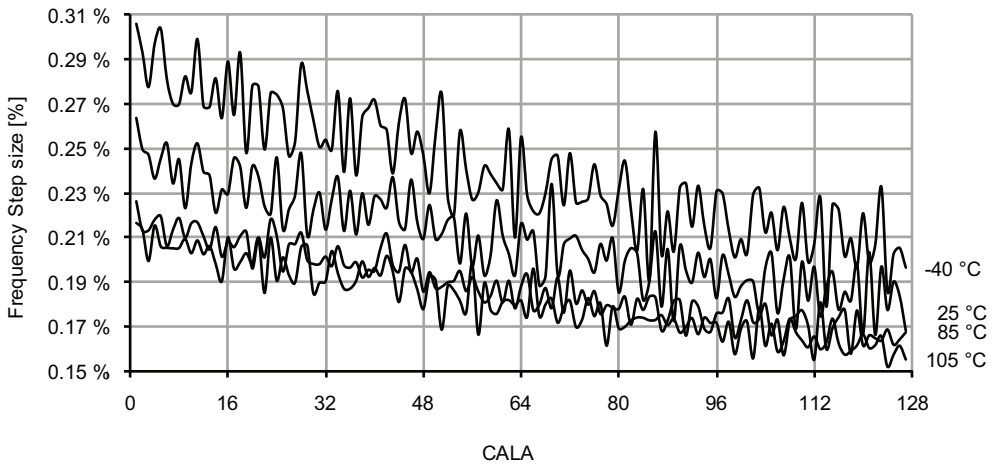


Figure 37-75. 2MHz internal oscillator CALA calibration step size.

V_{CC} = 3V.



37.2.2.3 Thresholds and Hysteresis

Figure 37-116. I/O pin input threshold voltage vs. V_{CC}.
T = 25°C.

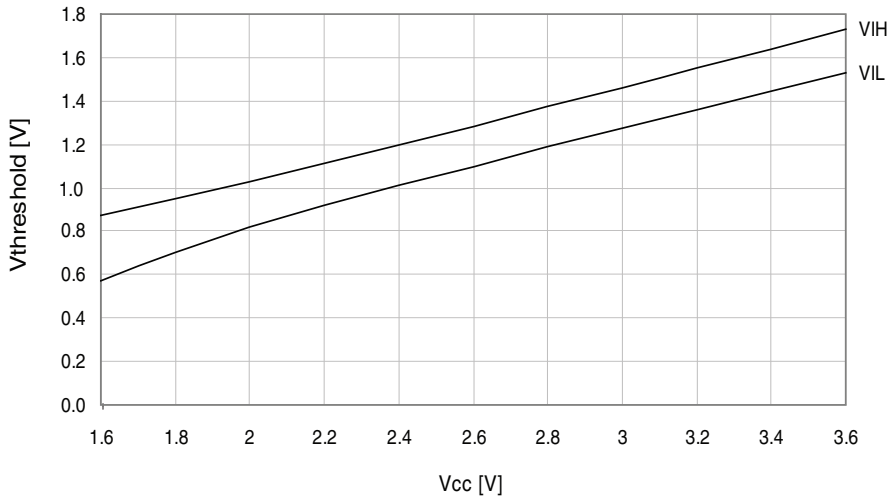


Figure 37-117. I/O pin input threshold voltage vs. V_{CC}.
V_{IH} I/O pin read as "1".

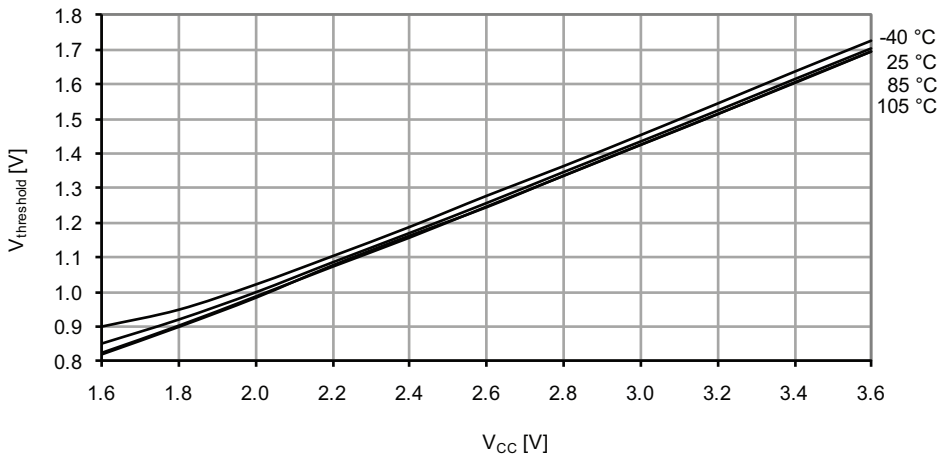


Figure 37-130. Offset error vs. V_{CC}.

T = 25°C, V_{REF} = external 1.0V, ADC sampling speed = 500ksps.

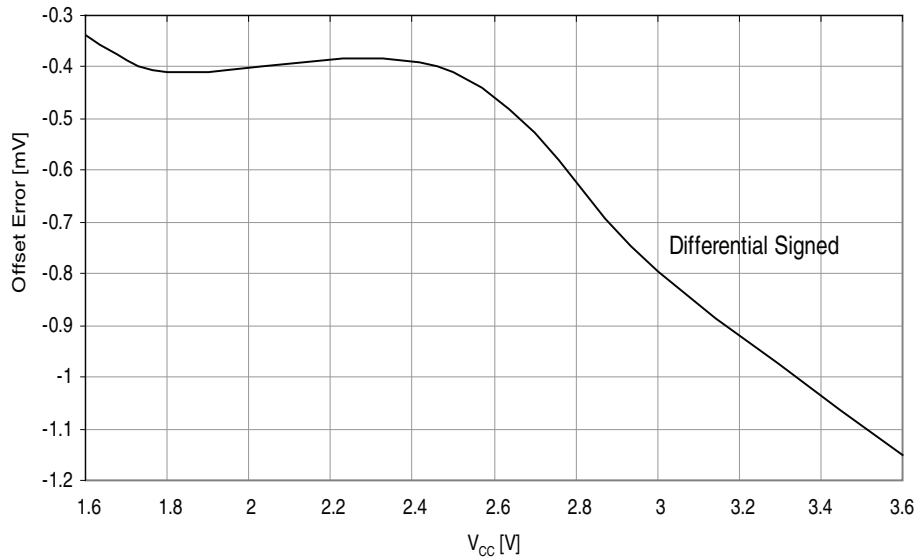
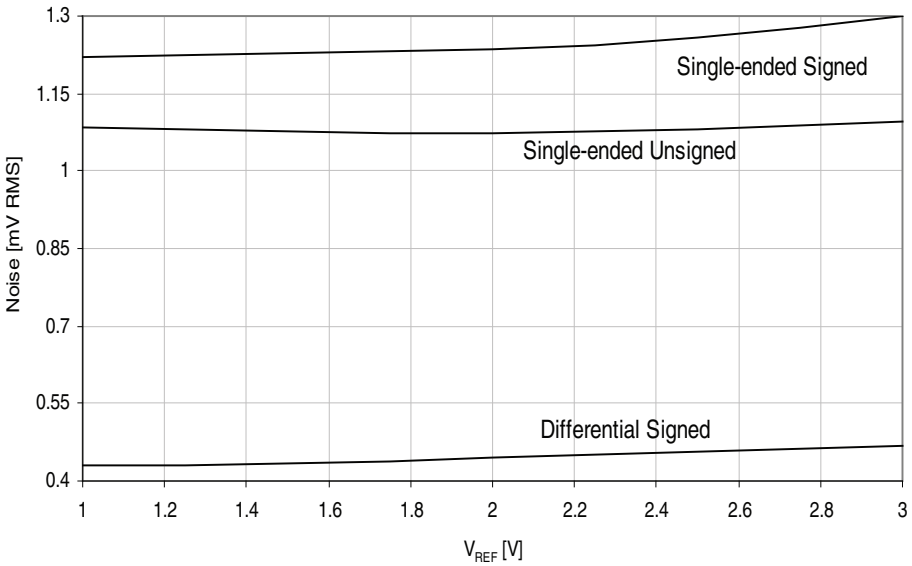


Figure 37-131. Noise vs. V_{REF}.

T = 25°C, V_{CC} = 3.6V, ADC sampling speed = 500ksps.



37.2.10.4 32MHz Internal Oscillator

Figure 37-160. 32MHz internal oscillator frequency vs. temperature.

DFLL disabled.

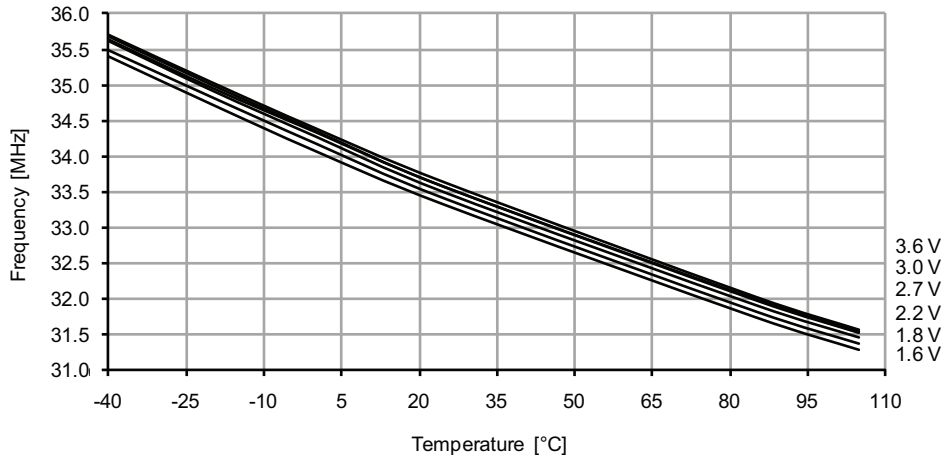
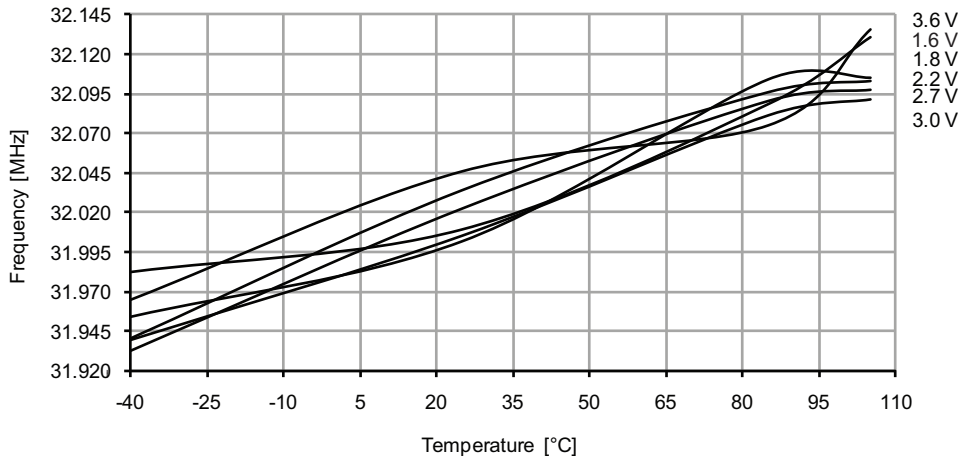


Figure 37-161. 32MHz internal oscillator frequency vs. temperature.

DFLL enabled, from the 32.768kHz internal oscillator.



37.2.10.5 32MHz internal oscillator calibrated to 48MHz

Figure 37-164. 48MHz internal oscillator frequency vs. temperature.

DFLL disabled.

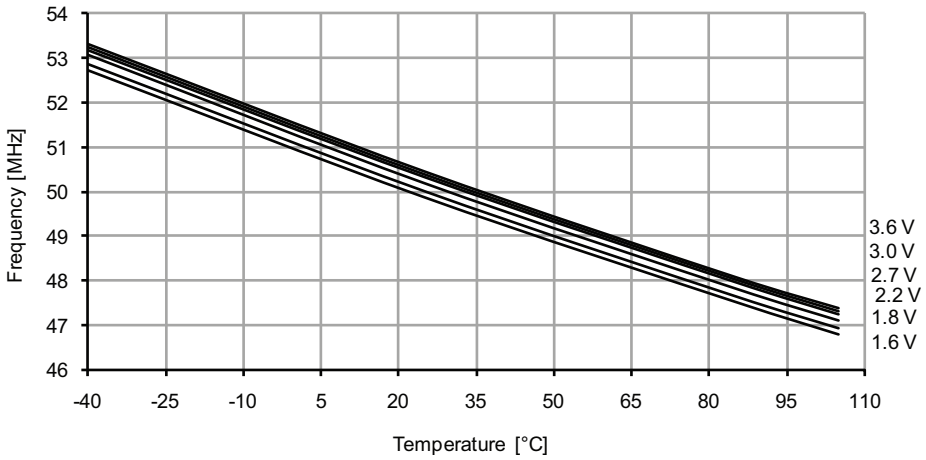
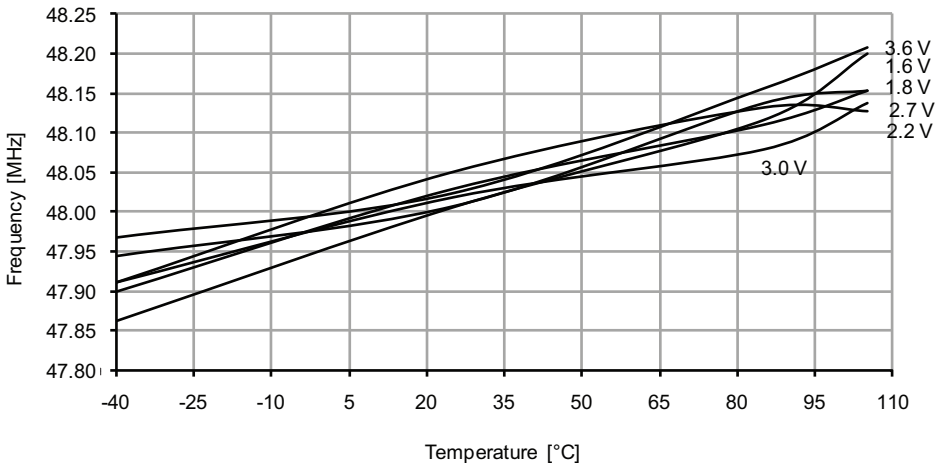


Figure 37-165. 48MHz internal oscillator frequency vs. temperature.

DFLL enabled, from the 32.768kHz internal oscillator.



37.2.12 PDI characteristics

Figure 37-168. Maximum PDI frequency vs. V_{CC}.

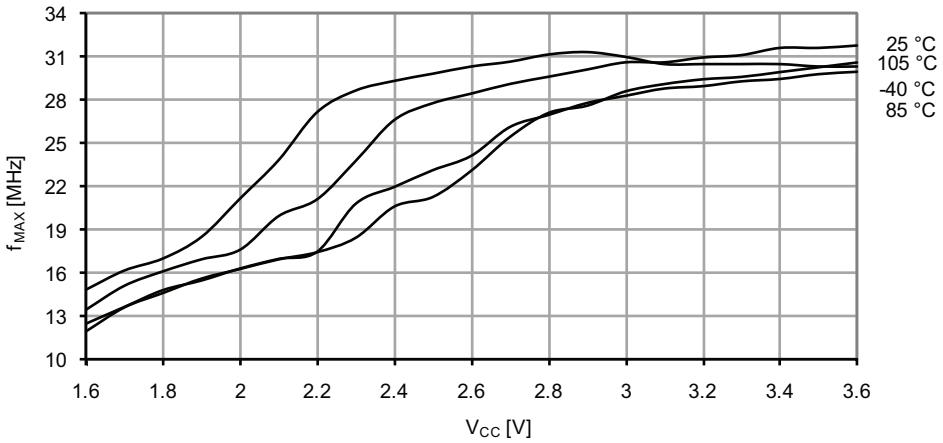
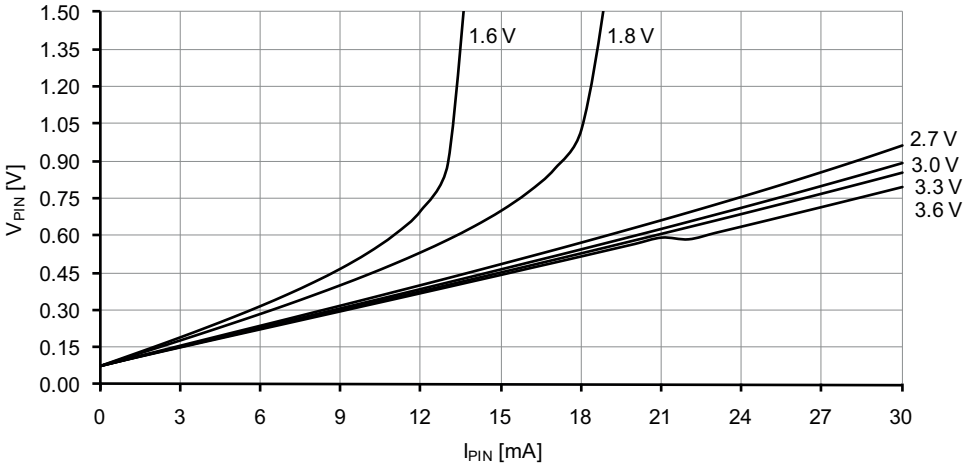


Figure 37-199. I/O pin output voltage vs. sink current.



37.3.2.3 Thresholds and Hysteresis

Figure 37-200. I/O pin input threshold voltage vs. V_{CC}.
T = 25°C.

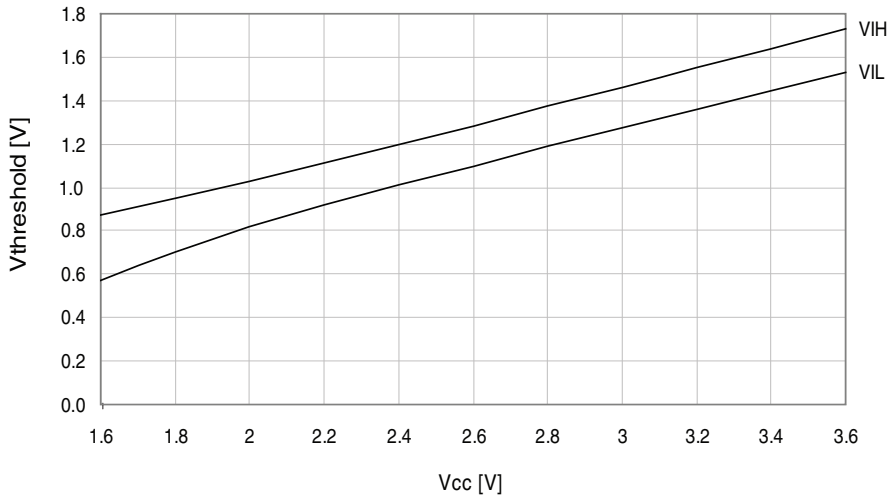


Figure 37-209. DNL error vs. input code.

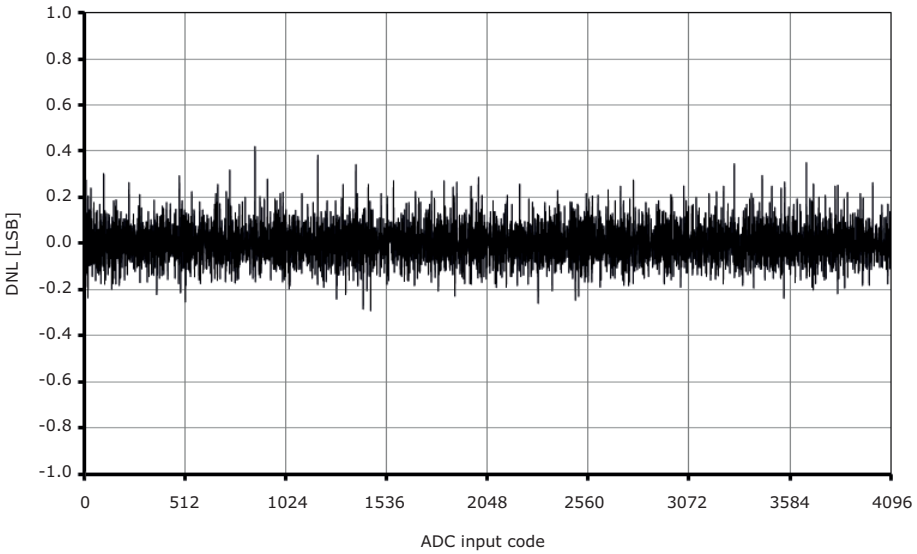
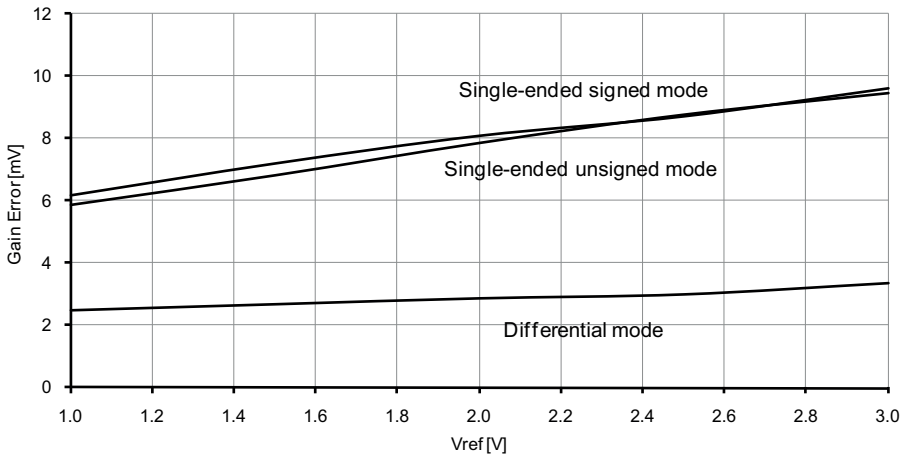


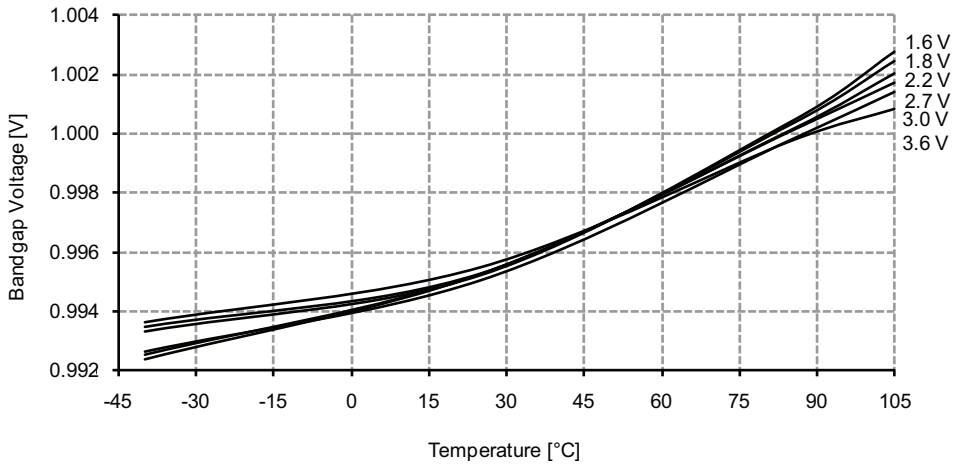
Figure 37-210. Gain error vs. V_{REF}.

T = 25°C, V_{CC} = 3.6V, ADC sampling speed = 500ksps.



37.3.6 Internal 1.0V reference Characteristics

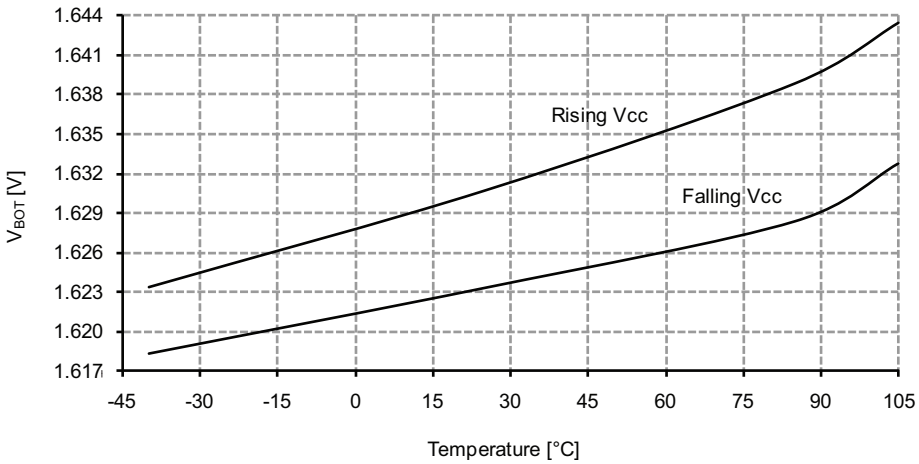
Figure 37-227. ADC/DAC Internal 1.0V reference vs. temperature.



37.3.7 BOD Characteristics

Figure 37-228. BOD thresholds vs. temperature.

BOD level = 1.6V.



37.4.1.5 Standby mode supply current

Figure 37-271. Standby supply current vs. V_{CC}.

Standby, f_{SYS} = 1MHz

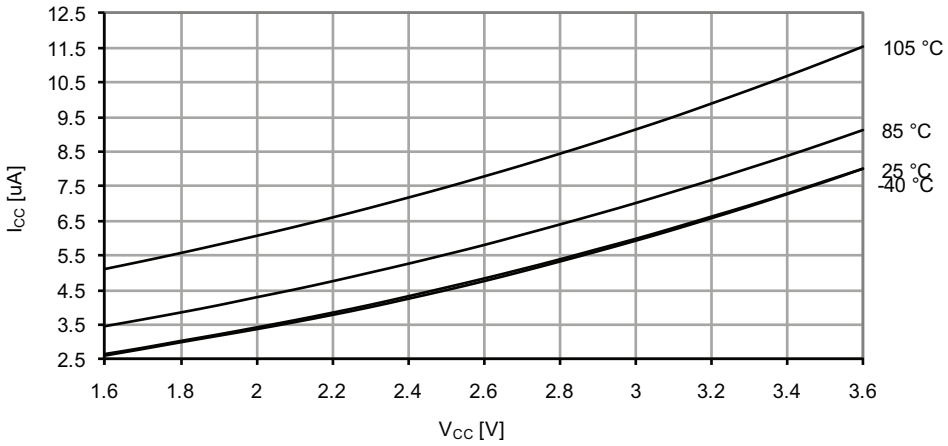
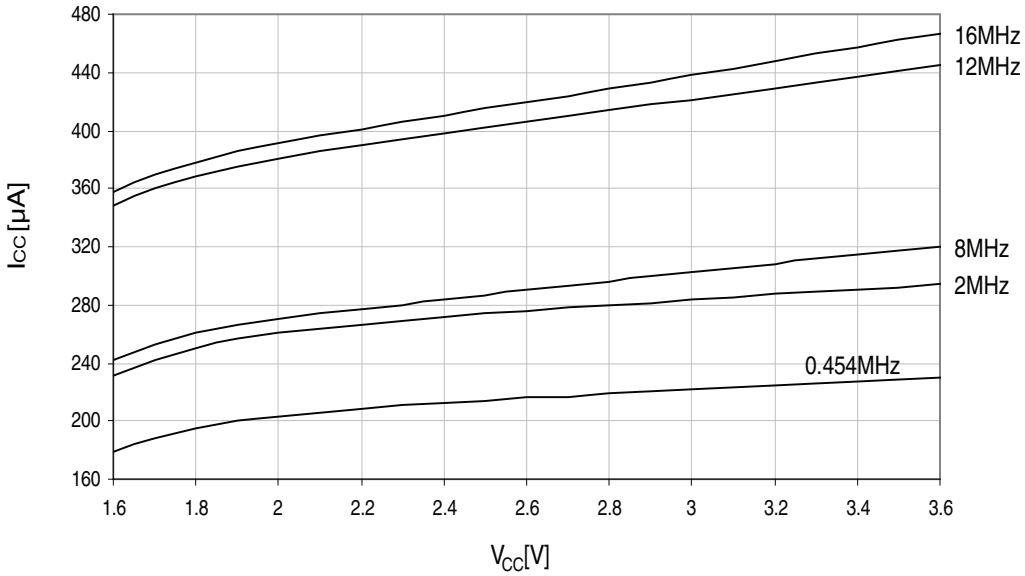


Figure 37-272. Standby supply current vs. V_{CC}.

T = 25°C, running from different crystal oscillators



38.4 ATxmega128A4U

38.4.1 rev. A

- ADC may have missing codes in SE unsigned mode at low temp and low Vcc

1. **ADC may have missing codes in SE unsigned mode at low temp and low Vcc**
   The ADC may have missing codes i single ended (SE) unsigned mode below 0C when Vcc is below 1.8V.

   Problem fix/Workaround
   Use the ADC in SE signed mode.